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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/780,303	02/17/2004	Masaaki Oka	450137-05004	9718

7590 05/08/2008
William S. Frommer, Esq.
FROMMER LAWRENCE & HAUG LLP
745 Fifth Avenue
New York, NY 10151

EXAMINER

LEE, JOHN W

ART UNIT	PAPER NUMBER
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2624

MAIL DATE	DELIVERY MODE
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05/08/2008

PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Attachment to Advisory Action

The examiner reviewed the applicant's argument. The examiner does not agree with the applicant and the prior art used for the final office action can read on the claims.

Satoh's "AR Game Apparatus" (Fig. 1-104 and Fig. 7) can be a database because it has a RAM (Fig. 7-703; paragraph [0093]) that can store images.

Applicant argues that Satoh does not disclose or teach the first shape which represents a three dimensional shape of a first area including at least a part of an object area in a real world. However, Satoh's "table" (Fig. 1-105; paragraphs [0037] and [0038]) is a three dimensional shape of object that can be in a real world. The examiner understands the difference between this claim limitation and the prior art, but the examiner only examines on the merit of the claims giving the broadest interpretation. If the applicant specified the "object area in a real world", then the applicant could have overcome the examiner's rejection of this claim limitation.

Moreover, the applicant did not recite "complementing an area in the object area not shot by a camera with an image of a first area generated from the first shaped data of the real world" in the claims. Instead, the applicant just recited "complementing an area in the object area not shot by a camera with an image of a first area generated from the first shaped data" in the claims. If the applicant had changed "first area" and "first shape data" in lines 6, 8, 9, 10, 13, 17 in claim 1 as "said first area" and "said first shape data", then Satoh could not be used as one of the prior art to reject the claims.

For other rejections, the examiner recommends the applicant to refer the second office action mailed on 4 January 2008.

The examiner suggests the applicant to amend at least the independent claims by specifying the claim limitations and the key terms if the applicant wants this case to be reconsidered and have a better chance for allowance.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to JOHN Wahnkyo LEE whose telephone number is (571)272-9554. The examiner can normally be reached on Monday - Friday (Alt.) 7:30 a.m. - 5:00 p.m..

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Jingge Wu can be reached on (571) 272-7429. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300. Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO

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Customer Service Representative or access to the automated information system, call
800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/Jingge Wu/

Supervisory Patent Examiner, Art Unit 2624

/John Wahnkyo Lee/

Examiner, Art Unit 2624